Search Notes

Application/Control N	•
10/609,490	
Examiner	
Donnia Muint	

Applicant(s)/Patent under
Reexamination
LEE, SHIH-JONG J.
Art Unit

2162

	SEARCHED				
Class	Subclass	Date	Examiner		
707	5,6, 100, 102, 200	8/17/2006	DM		
706	20, 16	8/17/2006	DM		
700	47, 51	8/17/2006	DM		
370	255	8/17/2006	V		
382	224	8/17/2006	DM		
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INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			
707	100, 102	8/17/2006	DM			
707	5, 6	8/17/2006	DM			
707	200	08/17/2016	2m			
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST (EPO; JPO; IBM; USPAT)	8/17/2006	DM
NPL: IEEE (Xplore)	8/17/2006	DM
NPL (Google)	8/17/2006	DM
Consulted with Marc Bookbinder for 101 issues. Claims are all stautory.	8/16/2006	DM
NPL: ACM	8/17/2006	DM
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